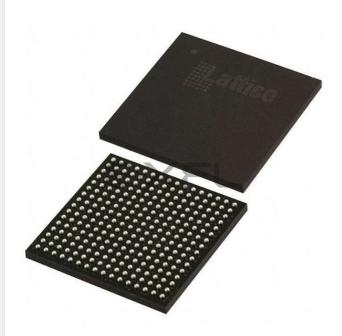
E ·) (Fatt ce Semiconductor Corporation - <u>LCMXO2-7000ZE-1FTG256I Datasheet</u>



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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	858
Number of Logic Elements/Cells	6864
Total RAM Bits	245760
Number of I/O	206
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FTBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmxo2-7000ze-1ftg256i

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Figure 2-4. Slice Diagram



For Slices 0 and 1, memory control signals are generated from Slice 2 as follows:

- WCK is CLK
 WRE is from LSR
- DI[3:2] for Slice 1 and DI[1:0] for Slice 0 data from Slice 2
- WAD [A:D] is a 4-bit address from slice 2 LUT input

 Table 2-2. Slice Signal Descriptions

Function	Туре	Signal Names	Description	
Input	Data signal	A0, B0, C0, D0	Inputs to LUT4	
Input	Data signal	A1, B1, C1, D1	Inputs to LUT4	
Input	Multi-purpose	M0/M1	Multi-purpose input	
Input	Control signal	CE	Clock enable	
Input	Control signal	LSR	Local set/reset	
Input	Control signal	CLK	System clock	
Input	Inter-PFU signal	FCIN	Fast carry in ¹	
Output	Data signals	F0, F1	LUT4 output register bypass signals	
Output	Data signals	Q0, Q1	Register outputs	
Output	Data signals	OFX0	Output of a LUT5 MUX	
Output	Data signals	OFX1	Output of a LUT6, LUT7, LUT8 ² MUX depending on the slice	
Output	Inter-PFU signal	FCO	Fast carry out ¹	

1. See Figure 2-3 for connection details.

2. Requires two PFUs.



Figure 2-8. sysMEM Memory Primitives



Table 2-6. EBR Signal Descriptions

Port Name	Description	Active State
CLK	Clock	Rising Clock Edge
CE	Clock Enable	Active High
OCE ¹	Output Clock Enable	Active High
RST	Reset	Active High
BE ¹	Byte Enable	Active High
WE	Write Enable	Active High
AD	Address Bus	—
DI	Data In	—
DO	Data Out	—
CS	Chip Select	Active High
AFF	FIFO RAM Almost Full Flag	—
FF	FIFO RAM Full Flag	—
AEF	FIFO RAM Almost Empty Flag	—
EF	FIFO RAM Empty Flag	—
RPRST	FIFO RAM Read Pointer Reset	—

1. Optional signals.

2. For dual port EBR primitives a trailing 'A' or 'B' in the signal name specifies the EBR port A or port B respectively.

3. For FIFO RAM mode primitive, a trailing 'R' or 'W' in the signal name specifies the FIFO read port or write port respectively.

4. For FIFO RAM mode primitive FULLI has the same function as CSW(2) and EMPTYI has the same function as CSR(2).

5. In FIFO mode, CLKW is the write port clock, CSW is the write port chip select, CLKR is the read port clock, CSR is the read port chip select, ORE is the output read enable.



The EBR memory supports three forms of write behavior for single or dual port operation:

- 1. **Normal** Data on the output appears only during the read cycle. During a write cycle, the data (at the current address) does not appear on the output. This mode is supported for all data widths.
- 2. Write Through A copy of the input data appears at the output of the same port. This mode is supported for all data widths.
- 3. Read-Before-Write When new data is being written, the old contents of the address appears at the output.

FIFO Configuration

The FIFO has a write port with data-in, CEW, WE and CLKW signals. There is a separate read port with data-out, RCE, RE and CLKR signals. The FIFO internally generates Almost Full, Full, Almost Empty and Empty Flags. The Full and Almost Full flags are registered with CLKW. The Empty and Almost Empty flags are registered with CLKR. Table 2-7 shows the range of programming values for these flags.

Table 2-7. Programmable FIFO Flag Ranges

Flag Name	Programming Range		
Full (FF)	1 to max (up to 2^{N} -1)		
Almost Full (AF)	1 to Full-1		
Almost Empty (AE)	1 to Full-1		
Empty (EF)	0		

N = Address bit width.

The FIFO state machine supports two types of reset signals: RST and RPRST. The RST signal is a global reset that clears the contents of the FIFO by resetting the read/write pointer and puts the FIFO flags in their initial reset state. The RPRST signal is used to reset the read pointer. The purpose of this reset is to retransmit the data that is in the FIFO. In these applications it is important to keep careful track of when a packet is written into or read from the FIFO.

Memory Core Reset

The memory core contains data output latches for ports A and B. These are simple latches that can be reset synchronously or asynchronously. RSTA and RSTB are local signals, which reset the output latches associated with port A and port B respectively. The Global Reset (GSRN) signal resets both ports. The output data latches and associated resets for both ports are as shown in Figure 2-9.







Tri-state Register Block

The tri-state register block registers tri-state control signals from the core of the device before they are passed to the sysIO buffers. The block contains a register for SDR operation. In SDR, TD input feeds one of the flip-flops that then feeds the output.

The tri-state register blocks on the right edge contain an additional register for DDR memory operation. In DDR memory mode, the register TS input is fed into another register that is clocked using the DQSW90 signal. The output of this register is used as a tri-state control.

Input Gearbox

Each PIC on the bottom edge has a built-in 1:8 input gearbox. Each of these input gearboxes may be programmed as a 1:7 de-serializer or as one IDDRX4 (1:8) gearbox or as two IDDRX2 (1:4) gearboxes. Table 2-9 shows the gearbox signals.

Name	I/O Type	Description
D	Input	High-speed data input after programmable delay in PIO A input register block
ALIGNWD	Input	Data alignment signal from device core
SCLK	Input	Slow-speed system clock
ECLK[1:0]	Input	High-speed edge clock
RST	Input	Reset
Q[7:0]	Output	Low-speed data to device core: Video RX(1:7): Q[6:0] GDDRX4(1:8): Q[7:0] GDDRX2(1:4)(IOL-A): Q4, Q5, Q6, Q7 GDDRX2(1:4)(IOL-C): Q0, Q1, Q2, Q3



MachXO2-640U, MachXO2-1200/U, MachXO2-2000/U, MachXO2-4000 and MachXO2-7000 devices contain three types of sysIO buffer pairs.

1. Left and Right sysIO Buffer Pairs

The sysIO buffer pairs in the left and right banks of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the left and right of the devices also have differential and referenced input buffers.

2. Bottom sysIO Buffer Pairs

The sysIO buffer pairs in the bottom bank of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the bottom also have differential and referenced input buffers. Only the I/Os on the bottom banks have programmable PCI clamps and differential input termination. The PCI clamp is enabled after V_{CC} and V_{CCIO} are at valid operating levels and the device has been configured.

3. Top sysIO Buffer Pairs

The sysIO buffer pairs in the top bank of the device consist of two single-ended output drivers and two singleended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the top also have differential and referenced I/O buffers. Half of the sysIO buffer pairs on the top edge have true differential outputs. The sysIO buffer pair comprising of the A and B PIOs in every PIC on the top edge have a differential output driver. The referenced input buffer can also be configured as a differential input buffer.

Typical I/O Behavior During Power-up

The internal power-on-reset (POR) signal is deactivated when V_{CC} and V_{CCIO0} have reached V_{PORUP} level defined in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet. After the POR signal is deactivated, the FPGA core logic becomes active. It is the user's responsibility to ensure that all V_{CCIO} banks are active with valid input logic levels to properly control the output logic states of all the I/O banks that are critical to the application. The default configuration of the I/O pins in a blank device is tri-state with a weak pulldown to GND (some pins such as PROGRAMN and the JTAG pins have weak pull-up to V_{CCIO} as the default functionality). The I/O pins will maintain the blank configuration until V_{CC} and V_{CCIO} (for I/O banks containing configuration I/Os) have reached V_{PORUP} levels at which time the I/Os will take on the user-configured settings only after a proper download/configuration.

Supported Standards

The MachXO2 sysIO buffer supports both single-ended and differential standards. Single-ended standards can be further subdivided into LVCMOS, LVTTL, and PCI. The buffer supports the LVTTL, PCI, LVCMOS 1.2, 1.5, 1.8, 2.5, and 3.3 V standards. In the LVCMOS and LVTTL modes, the buffer has individually configurable options for drive strength, bus maintenance (weak pull-up, weak pull-down, bus-keeper latch or none) and open drain. BLVDS, MLVDS and LVPECL output emulation is supported on all devices. The MachXO2-640U, MachXO2-1200/U and higher devices support on-chip LVDS output buffers on approximately 50% of the I/Os on the top bank. Differential receivers for LVDS, BLVDS, MLVDS and LVPECL are supported on all banks of MachXO2 devices. PCI support is provided in the bottom bank of theMachXO2-640U, MachXO2-1200/U and higher density devices. Table 2-11 summarizes the I/O characteristics of the MachXO2 PLDs.

Tables 2-11 and 2-12 show the I/O standards (together with their supply and reference voltages) supported by the MachXO2 devices. For further information on utilizing the sysIO buffer to support a variety of standards please see TN1202, MachXO2 sysIO Usage Guide.



For more details on these embedded functions, please refer to TN1205, Using User Flash Memory and Hardened Control Functions in MachXO2 Devices.

User Flash Memory (UFM)

MachXO2-640/U and higher density devices provide a User Flash Memory block, which can be used for a variety of applications including storing a portion of the configuration image, initializing EBRs, to store PROM data or, as a general purpose user Flash memory. The UFM block connects to the device core through the embedded function block WISHBONE interface. Users can also access the UFM block through the JTAG, I²C and SPI interfaces of the device. The UFM block offers the following features:

- Non-volatile storage up to 256 kbits
- 100K write cycles
- Write access is performed page-wise; each page has 128 bits (16 bytes)
- Auto-increment addressing
- WISHBONE interface

For more information on the UFM, please refer to TN1205, Using User Flash Memory and Hardened Control Functions in MachXO2 Devices.

Standby Mode and Power Saving Options

MachXO2 devices are available in three options for maximum flexibility: ZE, HC and HE devices. The ZE devices have ultra low static and dynamic power consumption. These devices use a 1.2 V core voltage that further reduces power consumption. The HC and HE devices are designed to provide high performance. The HC devices have a built-in voltage regulator to allow for 2.5 V V_{CC} and 3.3 V V_{CC} while the HE devices operate at 1.2 V V_{CC}.

MachXO2 devices have been designed with features that allow users to meet the static and dynamic power requirements of their applications by controlling various device subsystems such as the bandgap, power-on-reset circuitry, I/O bank controllers, power guard, on-chip oscillator, PLLs, etc. In order to maximize power savings, MachXO2 devices support an ultra low power Stand-by mode. While most of these features are available in all three device types, these features are mainly intended for use with MachXO2 ZE devices to manage power consumption.

In the stand-by mode the MachXO2 devices are powered on and configured. Internal logic, I/Os and memories are switched on and remain operational, as the user logic waits for an external input. The device enters this mode when the standby input of the standby controller is toggled or when an appropriate I²C or JTAG instruction is issued by an external master. Various subsystems in the device such as the band gap, power-on-reset circuitry etc can be configured such that they are automatically turned "off" or go into a low power consumption state to save power when the device enters this state. Note that the MachXO2 devices are powered on when in standby mode and all power supplies should remain in the Recommended Operating Conditions.



Device Subsystem	Feature Description
Bandgap	The bandgap can be turned off in standby mode. When the Bandgap is turned off, ana- log circuitry such as the POR, PLLs, on-chip oscillator, and referenced and differential I/O buffers are also turned off. Bandgap can only be turned off for 1.2 V devices.
Power-On-Reset (POR)	The POR can be turned off in standby mode. This monitors VCC levels. In the event of unsafe V_{CC} drops, this circuit reconfigures the device. When the POR circuitry is turned off, limited power detector circuitry is still active. This option is only recommended for applications in which the power supply rails are reliable.
On-Chip Oscillator	The on-chip oscillator has two power saving features. It may be switched off if it is not needed in your design. It can also be turned off in Standby mode.
PLL	Similar to the on-chip oscillator, the PLL also has two power saving features. It can be statically switched off if it is not needed in a design. It can also be turned off in Standby mode. The PLL will wait until all output clocks from the PLL are driven low before powering off.
I/O Bank Controller	Referenced and differential I/O buffers (used to implement standards such as HSTL, SSTL and LVDS) consume more than ratioed single-ended I/Os such as LVCMOS and LVTTL. The I/O bank controller allows the user to turn these I/Os off dynamically on a per bank selection.
Dynamic Clock Enable for Primary Clock Nets	Each primary clock net can be dynamically disabled to save power.
Power Guard	Power Guard is a feature implemented in input buffers. This feature allows users to switch off the input buffer when it is not needed. This feature can be used in both clock and data paths. Its biggest impact is that in the standby mode it can be used to switch off clock inputs that are distributed using general routing resources.

For more details on the standby mode refer to TN1198, Power Estimation and Management for MachXO2 Devices.

Power On Reset

MachXO2 devices have power-on reset circuitry to monitor V_{CCINT} and V_{CCIO} voltage levels during power-up and operation. At power-up, the POR circuitry monitors V_{CCINT} and V_{CCIO0} (controls configuration) voltage levels. It then triggers download from the on-chip configuration Flash memory after reaching the V_{PORUP} level specified in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet. For devices without voltage regulators (ZE and HE devices), V_{CCINT} is the same as the V_{CC} supply voltage. For devices with voltage regulators (HC devices), V_{CCINT} is regulated from the V_{CC} supply voltage. From this voltage reference, the time taken for configuration and entry into user mode is specified as Flash Download Time (t_{REFRESH}) in the DC and Switching Characteristics section of this data sheet. Before and during configuration, the I/Os are held in tristate. I/Os are released to user functionality once the device has finished configuration. Note that for HC devices, a separate POR circuit monitors external V_{CC} voltage in addition to the POR circuit that monitors the internal post-regulated power supply voltage level.

Once the device enters into user mode, the POR circuitry can optionally continue to monitor V_{CCINT} levels. If V_{CCINT} drops below $V_{PORDNBG}$ level (with the bandgap circuitry switched on) or below $V_{PORDNSRAM}$ level (with the bandgap circuitry switched off to conserve power) device functionality cannot be guaranteed. In such a situation the POR issues a reset and begins monitoring the V_{CCINT} and V_{CCIO} voltage levels. $V_{PORDNBG}$ and $V_{PORDNSRAM}$ are both specified in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet.

Note that once a ZE or HE device enters user mode, users can switch off the bandgap to conserve power. When the bandgap circuitry is switched off, the POR circuitry also shuts down. The device is designed such that a minimal, low power POR circuit is still operational (this corresponds to the $V_{PORDNSRAM}$ reset point described in the paragraph above). However this circuit is not as accurate as the one that operates when the bandgap is switched on. The low power POR circuit emulates an SRAM cell and is biased to trip before the vast majority of SRAM cells flip. If users are concerned about the V_{CC} supply dropping below V_{CC} (min) they should not shut down the bandgap or POR circuit.



DC Electrical Characteristics

Symbol	Parameter	Condition	Min.	Тур.	Max.	Units
ا _{ال} , ا _{ال} ا ^{1, 4}		Clamp OFF and $V_{CCIO} < V_{IN} < V_{IH}$ (MAX)	_	_	+175	μΑ
		Clamp OFF and $V_{IN} = V_{CCIO}$	-10		10	μA
	Input or I/O Leakage	Clamp OFF and V _{CCIO} –0.97 V < V _{IN} < V _{CCIO}	-175	_	—	μA
		Clamp OFF and 0 V < V _{IN} < V _{CCIO} –0.97 V			10	μA
		Clamp OFF and V _{IN} = GND	—	_	10	μΑ
		Clamp ON and 0 V < V_{IN} < V_{CCIO}	_	_	10	μΑ
I _{PU}	I/O Active Pull-up Current	0 < V _{IN} < 0.7 V _{CCIO}	-30		-309	μA
I _{PD}	I/O Active Pull-down Current	V_{IL} (MAX) < V_{IN} < V_{CCIO}	30		305	μA
I _{BHLS}	Bus Hold Low sustaining current	$V_{IN} = V_{IL} (MAX)$	30		_	μA
I _{BHHS}	Bus Hold High sustaining current	$V_{IN} = 0.7 V_{CCIO}$	-30		_	μA
I _{BHLO}	Bus Hold Low Overdrive current	$0 \leq V_{IN} \leq V_{CCIO}$	_		305	μA
I _{BHHO}	Bus Hold High Overdrive current	$0 \leq V_{IN} \leq V_{CCIO}$	_		-309	μA
V _{BHT} ³	Bus Hold Trip Points		V _{IL} (MAX)		V _{IH} (MIN)	V
C1	I/O Capacitance ²	$V_{CCIO} = 3.3 \text{ V}, 2.5 \text{ V}, 1.8 \text{ V}, 1.5 \text{ V}, 1.2 \text{ V}, V_{CC} = Typ., V_{IO} = 0 \text{ to } V_{IH} \text{ (MAX)}$	3	5	9	pF
C2	Dedicated Input Capacitance ²	$V_{CCIO} = 3.3 \text{ V}, 2.5 \text{ V}, 1.8 \text{ V}, 1.5 \text{ V}, 1.2 \text{ V}, V_{CC} = Typ., V_{IO} = 0 \text{ to } V_{IH} \text{ (MAX)}$	3	5.5	7	pF
		V _{CCIO} = 3.3 V, Hysteresis = Large	_	450	—	mV
		V _{CCIO} = 2.5 V, Hysteresis = Large	_	250	—	mV
	Hysteresis for Schmitt Trigger Inputs⁵	V _{CCIO} = 1.8 V, Hysteresis = Large	_	125	—	mV
V _{HYST}		V _{CCIO} = 1.5 V, Hysteresis = Large	_	100	—	mV
		V _{CCIO} = 3.3 V, Hysteresis = Small	—	250	—	mV
		V _{CCIO} = 2.5 V, Hysteresis = Small	—	150	—	mV
		V _{CCIO} = 1.8 V, Hysteresis = Small	—	60	—	mV
		V _{CCIO} = 1.5 V, Hysteresis = Small	_	40	—	mV

1. Input or I/O leakage current is measured with the pin configured as an input or as an I/O with the output driver tri-stated. It is not measured with the output driver active. Bus maintenance circuits are disabled.

2. T_A 25 °C, f = 1.0 MHz.

3. Please refer to V_{IL} and V_{IH} in the sysIO Single-Ended DC Electrical Characteristics table of this document.

4. When V_{IH} is higher than V_{CCIO}, a transient current typically of 30 ns in duration or less with a peak current of 6 mA can occur on the high-to-low transition. For true LVDS output pins in MachXO2-640U, MachXO2-1200/U and larger devices, V_{IH} must be less than or equal to V_{CCIO}.

5. With bus keeper circuit turned on. For more details, refer to TN1202, MachXO2 sysIO Usage Guide.



BLVDS

The MachXO2 family supports the BLVDS standard through emulation. The output is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs. The input standard is supported by the LVDS differential input buffer. BLVDS is intended for use when multi-drop and bi-directional multi-point differential signaling is required. The scheme shown in Figure 3-2 is one possible solution for bi-directional multi-point differential signals.

Figure 3-2. BLVDS Multi-point Output Example



Table 3-2. BLVDS DC Conditions¹

Over Recommended	Operating	Conditions
	oporating	00110110110

		Non		
Symbol	Description	Zo = 45	Zo = 90	Units
Z _{OUT}	Output impedance	20	20	Ohms
R _S	Driver series resistance	80	80	Ohms
R _{TLEFT}	Left end termination	45	90	Ohms
R _{TRIGHT}	Right end termination	45	90	Ohms
V _{OH}	Output high voltage	1.376	1.480	V
V _{OL}	Output low voltage	1.124	1.020	V
V _{OD}	Output differential voltage	0.253	0.459	V
V _{CM}	Output common mode voltage	1.250	1.250	V
I _{DC}	DC output current	11.236	10.204	mA

1. For input buffer, see LVDS table.



Typical Building Block Function Performance – HC/HE Devices¹

Pin-to-Pin Performance (LVCMOS25 12 mA Drive)

Function	-6 Timing	Units	
Basic Functions			
16-bit decoder	8.9	ns	
4:1 MUX	7.5	ns	
16:1 MUX	8.3	ns	

Register-to-Register Performance

Function	-6 Timing	Units
Basic Functions		
16:1 MUX	412	MHz
16-bit adder	297	MHz
16-bit counter	324	MHz
64-bit counter	161	MHz
Embedded Memory Functions		
1024x9 True-Dual Port RAM (Write Through or Normal, EBR output registers)	183	MHz
Distributed Memory Functions		
16x4 Pseudo-Dual Port RAM (one PFU)	500	MHz

 The above timing numbers are generated using the Diamond design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.



Typical Building Block Function Performance – ZE Devices¹

Pin-to-Pin Performance (LVCMOS25 12 mA Drive)

Function	–3 Timing	Units
Basic Functions		
16-bit decoder	13.9	ns
4:1 MUX	10.9	ns
16:1 MUX	12.0	ns

Register-to-Register Performance

–3 Timing	Units
191	MHz
134	MHz
148	MHz
77	MHz
90	MHz
214	MHz
	191 134 148 77 90

1. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device.

Derating Logic Timing

Logic timing provided in the following sections of the data sheet and the Lattice design tools are worst case numbers in the operating range. Actual delays may be much faster. Lattice design tools can provide logic timing numbers at a particular temperature and voltage.



			-	-6	_	5	_	4	
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
		MachXO2-1200HC-HE	0.41		0.48		0.55		ns
	Clock to Data Hold – PIO Input	MachXO2-2000HC-HE	0.42		0.49		0.56		ns
t _{HPLL}	Register	MachXO2-4000HC-HE	0.43		0.50	—	0.58	—	ns
		MachXO2-7000HC-HE	0.46		0.54	—	0.62	—	ns
		MachXO2-1200HC-HE	2.88	—	3.19	—	3.72	—	ns
	Clock to Data Setup – PIO	MachXO2-2000HC-HE	2.87	—	3.18	—	3.70	—	ns
t _{SU_DELPLL}	Input Register with Data Input Delay	MachXO2-4000HC-HE	2.96	—	3.28	—	3.81	—	ns
	MachXO2-7000HC-HE	3.05	—	3.35	—	3.87	—	ns	
		MachXO2-1200HC-HE	-0.83	—	-0.83		-0.83		ns
	Clock to Data Hold – PIO Input	MachXO2-2000HC-HE	-0.83	—	-0.83	—	-0.83	—	ns
^t H_DELPLL	Register with Input Data Delay	MachXO2-4000HC-HE	-0.87	—	-0.87	—	-0.87	—	ns
		MachXO2-7000HC-HE	-0.91	—	-0.91	—	-0.91	—	ns
Generic DDF	RX1 Inputs with Clock and Data	Aligned at Pin Using PC	LK Pin	for Cloc	k Input -	GDDR	(1_RX.S	CLK.Ali	gned ^{9, 12}
t _{DVA}	Input Data Valid After CLK			0.317		0.344		0.368	UI
t _{DVE}	Input Data Hold After CLK		0.742	—	0.702		0.668		UI
f _{DATA}	DDRX1 Input Data Speed	all sides	_	300	—	250	—	208	Mbps
f _{DDRX1}	DDRX1 SCLK Frequency		_	150	—	125	—	104	MHz
Generic DDF	X1 Inputs with Clock and Data C	Centered at Pin Using PC	LK Pin f	or Clock	Input –	GDDRX	1_RX.SC	LK.Cen	tered ^{9, 12}
t _{SU}	Input Data Setup Before CLK		0.566		0.560		0.538		ns
t _{HO}	Input Data Hold After CLK	All MachXO2 devices,	0.778		0.879	—	1.090	_	ns
f _{DATA}	DDRX1 Input Data Speed	all sides	_	300	—	250	—	208	Mbps
f _{DDRX1}	DDRX1 SCLK Frequency		_	150	—	125	—	104	MHz
Generic DDF	RX2 Inputs with Clock and Data	Aligned at Pin Using PC	LK Pin 1	for Clock	< Input –	GDDRX	2_RX.E	CLK.Alię	gned ^{9, 12}
t _{DVA}	Input Data Valid After CLK		—	0.316		0.342		0.364	UI
t _{DVE}	Input Data Hold After CLK	MachXO2-640U,	0.710		0.675	—	0.679	_	UI
f _{DATA}	DDRX2 Serial Input Data Speed	MachXO2-1200/U and larger devices,	_	664	_	554	_	462	Mbps
f _{DDRX2}	DDRX2 ECLK Frequency	bottom side only ¹¹	_	332	—	277	—	231	MHz
f _{SCLK}	SCLK Frequency		_	166	—	139	—	116	MHz
Generic DDF	X2 Inputs with Clock and Data C	Centered at Pin Using PC	LK Pin f	or Clock	Input –	GDDRX	2_RX.EC	LK.Cent	ered ^{9, 12}
t _{SU}	Input Data Setup Before CLK		0.233	—	0.219		0.198		ns
t _{HO}	Input Data Hold After CLK	MachXO2-640U,	0.287	—	0.287		0.344		ns
f _{DATA}	DDRX2 Serial Input Data Speed	MachXO2-1200/U and larger devices,	_	664	_	554	_	462	Mbps
f _{DDRX2}	DDRX2 ECLK Frequency	bottom side only ¹¹		332		277	_	231	MHz
f _{SCLK}	SCLK Frequency	1	_	166	_	139		116	MHz
	· · ·		L	l	1	1	1	1	



			_	-3	_	2	_	-1	
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
Generic DDR	2 Outputs with Clock and Data C	Centered at Pin Using P	CLK Pin	for Cloc	k Input –	GDDRX	2_TX.EC	CLK.Cen	tered ^{9, 12}
t _{DVB}	Output Data Valid Before CLK Output	MachXO2-640U,	1.445	_	1.760	_	2.140	_	ns
t _{DVA}	Output Data Valid After CLK Output		1.445	_	1.760	_	2.140	_	ns
f _{DATA}	DDRX2 Serial Output Data Speed	MachXO2-1200/U and larger devices, top side only	_	280		234	_	194	Mbps
f _{DDRX2}	DDRX2 ECLK Frequency (minimum limited by PLL)		_	140		117	_	97	MHz
f _{SCLK}	SCLK Frequency			70	_	59	—	49	MHz
Generic DDR	X4 Outputs with Clock and Data	Aligned at Pin Using P	CLK Pin	for Cloc	k Input	- GDDR	X4_TX.E	CLK.Ali	gned ^{9, 12}
t _{DIA}	Output Data Invalid After CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only	_	0.270	_	0.300	_	0.330	ns
t _{DIB}	Output Data Invalid Before CLK Output		_	0.270		0.300	_	0.330	ns
f _{DATA}	DDRX4 Serial Output Data Speed		_	420		352	_	292	Mbps
f _{DDRX4}	DDRX4 ECLK Frequency			210	_	176		146	MHz
f _{SCLK}	SCLK Frequency			53		44	—	37	MHz
Generic DDR	4 Outputs with Clock and Data C	entered at Pin Using P	CLK Pin	for Cloc	k Input –	GDDRX	4_TX.EC	LK.Cen	tered ^{9, 12}
t _{DVB}	Output Data Valid Before CLK Output		0.873	_	1.067	_	1.319	_	ns
t _{DVA}	Output Data Valid After CLK Output	MachXO2-640U,	0.873		1.067	_	1.319	_	ns
f _{DATA}	DDRX4 Serial Output Data Speed	MachXO2-1200/U and larger devices, top side only	_	420		352	_	292	Mbps
f _{DDRX4}	DDRX4 ECLK Frequency (minimum limited by PLL)		_	210		176	_	146	MHz
f _{SCLK}	SCLK Frequency			53	_	44	—	37	MHz
7:1 LVDS Out	tputs – GDDR71_TX.ECLK.7:1 ^s	, 12							
t _{DIB}	Output Data Invalid Before CLK Output		_	0.240	_	0.270	_	0.300	ns
t _{DIA}	Output Data Invalid After CLK Output	MachXO2-640U,	_	0.240		0.270	_	0.300	ns
f _{DATA}	DDR71 Serial Output Data Speed	MachXO2-1200/U and larger devices,	_	420	_	352	_	292	Mbps
f _{DDR71}	DDR71 ECLK Frequency	top side only.		210	_	176		146	MHz
fclkout	7:1 Output Clock Frequency (SCLK) (minimum limited by PLL)		_	60	_	50	_	42	MHz



sysCONFIG Port Timing Specifications

Symbol	Pa	Parameter		Max.	Units
All Configuration M	odes		1		
t _{PRGM}	PROGRAMN low p	oulse accept	55	—	ns
t _{PRGMJ}	PROGRAMN low p	oulse rejection	—	25	ns
t _{INITL}	INITN low time	LCMXO2-256	—	30	μs
		LCMXO2-640	—	35	μs
		LCMXO2-640U/ LCMXO2-1200	—	55	μs
		LCMXO2-1200U/ LCMXO2-2000	—	70	μs
		LCMXO2-2000U/ LCMXO2-4000	—	105	μs
		LCMXO2-7000	_	130	μs
t _{DPPINIT}	PROGRAMN low to	o INITN low	—	150	ns
t _{DPPDONE}	PROGRAMN low to	o DONE low	—	150	ns
t _{IODISS}	PROGRAMN low to	PROGRAMN low to I/O disable		120	ns
Slave SPI			•		
f _{MAX}	CCLK clock freque	ncy	—	66	MHz
t _{CCLKH}	CCLK clock pulse	width high	7.5	—	ns
t _{CCLKL}	CCLK clock pulse	width low	7.5	—	ns
t _{STSU}	CCLK setup time		2	—	ns
t _{STH}	CCLK hold time		0	—	ns
t _{STCO}	CCLK falling edge	to valid output	—	10	ns
t _{STOZ}	CCLK falling edge	to valid disable	—	10	ns
t _{STOV}	CCLK falling edge	to valid enable	—	10	ns
t _{SCS}	Chip select high tin	ne	25	—	ns
t _{SCSS}	Chip select setup t	ime	3	—	ns
t _{SCSH}	Chip select hold tin	ne	3	—	ns
Master SPI	·				
f _{MAX}	MCLK clock freque	ency	—	133	MHz
t _{MCLKH}	MCLK clock pulse	width high	3.75	—	ns
t _{MCLKL}	MCLK clock pulse	width low	3.75	—	ns
t _{STSU}	MCLK setup time			—	ns
t _{STH}	MCLK hold time		1	—	ns
t _{CSSPI}	INITN high to chip	select low	100	200	ns
t _{MCLK}	INITN high to first I	VCLK edge	0.75	1	μs



For Further Information

For further information regarding logic signal connections for various packages please refer to the MachXO2 Device Pinout Files.

Thermal Management

Thermal management is recommended as part of any sound FPGA design methodology. To assess the thermal characteristics of a system, Lattice specifies a maximum allowable junction temperature in all device data sheets. Users must complete a thermal analysis of their specific design to ensure that the device and package do not exceed the junction temperature limits. Refer to the Thermal Management document to find the device/package specific thermal values.

For Further Information

For further information regarding Thermal Management, refer to the following:

- Thermal Management document
- TN1198, Power Estimation and Management for MachXO2 Devices
- The Power Calculator tool is included with the Lattice design tools, or as a standalone download from www.latticesemi.com/software



Ordering Information

MachXO2 devices have top-side markings, for commercial and industrial grades, as shown below:



Notes:

- 1. Markings are abbreviated for small packages.
- 2. See PCN 05A-12 for information regarding a change to the top-side mark logo.



Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000UHC-4FG484C	2112	2.5 V / 3.3 V	-4	Halogen-Free fpBGA	484	COM
LCMXO2-2000UHC-5FG484C	2112	2.5 V / 3.3 V	-5	Halogen-Free fpBGA	484	COM
LCMXO2-2000UHC-6FG484C	2112	2.5 V / 3.3 V	-6	Halogen-Free fpBGA	484	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-4000HC-4QN84C	4320	2.5 V / 3.3 V	-4	Halogen-Free QFN	84	COM
LCMXO2-4000HC-5QN84C	4320	2.5 V / 3.3 V	-5	Halogen-Free QFN	84	COM
LCMXO2-4000HC-6QN84C	4320	2.5 V / 3.3 V	-6	Halogen-Free QFN	84	COM
LCMXO2-4000HC-4MG132C	4320	2.5 V / 3.3 V	-4	Halogen-Free csBGA	132	COM
LCMXO2-4000HC-5MG132C	4320	2.5 V / 3.3 V	-5	Halogen-Free csBGA	132	COM
LCMXO2-4000HC-6MG132C	4320	2.5 V / 3.3 V	-6	Halogen-Free csBGA	132	COM
LCMXO2-4000HC-4TG144C	4320	2.5 V / 3.3 V	-4	Halogen-Free TQFP	144	COM
LCMXO2-4000HC-5TG144C	4320	2.5 V / 3.3 V	-5	Halogen-Free TQFP	144	COM
LCMXO2-4000HC-6TG144C	4320	2.5 V / 3.3 V	-6	Halogen-Free TQFP	144	COM
LCMXO2-4000HC-4BG256C	4320	2.5 V / 3.3 V	-4	Halogen-Free caBGA	256	COM
LCMXO2-4000HC-5BG256C	4320	2.5 V / 3.3 V	-5	Halogen-Free caBGA	256	COM
LCMXO2-4000HC-6BG256C	4320	2.5 V / 3.3 V	-6	Halogen-Free caBGA	256	COM
LCMXO2-4000HC-4FTG256C	4320	2.5 V / 3.3 V	-4	Halogen-Free ftBGA	256	COM
LCMXO2-4000HC-5FTG256C	4320	2.5 V / 3.3 V	-5	Halogen-Free ftBGA	256	COM
LCMXO2-4000HC-6FTG256C	4320	2.5 V / 3.3 V	-6	Halogen-Free ftBGA	256	COM
LCMXO2-4000HC-4BG332C	4320	2.5 V / 3.3 V	-4	Halogen-Free caBGA	332	COM
LCMXO2-4000HC-5BG332C	4320	2.5 V / 3.3 V	-5	Halogen-Free caBGA	332	COM
LCMXO2-4000HC-6BG332C	4320	2.5 V / 3.3 V	-6	Halogen-Free caBGA	332	COM
LCMXO2-4000HC-4FG484C	4320	2.5 V / 3.3 V	-4	Halogen-Free fpBGA	484	COM
LCMXO2-4000HC-5FG484C	4320	2.5 V / 3.3 V	-5	Halogen-Free fpBGA	484	COM
LCMXO2-4000HC-6FG484C	4320	2.5 V / 3.3 V	-6	Halogen-Free fpBGA	484	COM



High-Performance Industrial Grade Devices with Voltage Regulator, Halogen Free (RoHS) Packaging

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-256HC-4SG32I	256	2.5 V / 3.3 V	-4	Halogen-Free QFN	32	IND
LCMXO2-256HC-5SG32I	256	2.5 V / 3.3 V	-5	Halogen-Free QFN	32	IND
LCMXO2-256HC-6SG32I	256	2.5 V / 3.3 V	-6	Halogen-Free QFN	32	IND
LCMXO2-256HC-4SG48I	256	2.5 V / 3.3 V	-4	Halogen-Free QFN	48	IND
LCMXO2-256HC-5SG48I	256	2.5 V / 3.3 V	-5	Halogen-Free QFN	48	IND
LCMXO2-256HC-6SG48I	256	2.5 V / 3.3 V	-6	Halogen-Free QFN	48	IND
LCMXO2-256HC-4UMG64I	256	2.5 V / 3.3 V	-4	Halogen-Free ucBGA	64	IND
LCMXO2-256HC-5UMG64I	256	2.5 V / 3.3 V	-5	Halogen-Free ucBGA	64	IND
LCMXO2-256HC-6UMG64I	256	2.5 V / 3.3 V	-6	Halogen-Free ucBGA	64	IND
LCMXO2-256HC-4TG100I	256	2.5 V / 3.3 V	-4	Halogen-Free TQFP	100	IND
LCMXO2-256HC-5TG100I	256	2.5 V / 3.3 V	-5	Halogen-Free TQFP	100	IND
LCMXO2-256HC-6TG100I	256	2.5 V / 3.3 V	-6	Halogen-Free TQFP	100	IND
LCMXO2-256HC-4MG132I	256	2.5 V / 3.3 V	-4	Halogen-Free csBGA	132	IND
LCMXO2-256HC-5MG132I	256	2.5 V / 3.3 V	-5	Halogen-Free csBGA	132	IND
LCMXO2-256HC-6MG132I	256	2.5 V / 3.3 V	-6	Halogen-Free csBGA	132	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-640HC-4SG48I	640	2.5 V / 3.3 V	-4	Halogen-Free QFN	48	IND
LCMXO2-640HC-5SG48I	640	2.5 V / 3.3 V	-5	Halogen-Free QFN	48	IND
LCMXO2-640HC-6SG48I	640	2.5 V / 3.3 V	-6	Halogen-Free QFN	48	IND
LCMXO2-640HC-4TG100I	640	2.5 V / 3.3 V	-4	Halogen-Free TQFP	100	IND
LCMXO2-640HC-5TG100I	640	2.5 V / 3.3 V	-5	Halogen-Free TQFP	100	IND
LCMXO2-640HC-6TG100I	640	2.5 V / 3.3 V	-6	Halogen-Free TQFP	100	IND
LCMXO2-640HC-4MG132I	640	2.5 V / 3.3 V	-4	Halogen-Free csBGA	132	IND
LCMXO2-640HC-5MG132I	640	2.5 V / 3.3 V	-5	Halogen-Free csBGA	132	IND
LCMXO2-640HC-6MG132I	640	2.5 V / 3.3 V	-6	Halogen-Free csBGA	132	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-640UHC-4TG144I	640	2.5 V / 3.3 V	-4	Halogen-Free TQFP	144	IND
LCMXO2-640UHC-5TG144I	640	2.5 V / 3.3 V	-5	Halogen-Free TQFP	144	IND
LCMXO2-640UHC-6TG144I	640	2.5 V / 3.3 V	-6	Halogen-Free TQFP	144	IND



High Performance Industrial Grade Devices Without Voltage Regulator, Halogen Free (RoHS) Packaging

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000HE-4TG100I	2112	1.2 V	-4	Halogen-Free TQFP	100	IND
LCMXO2-2000HE-5TG100I	2112	1.2 V	-5	Halogen-Free TQFP	100	IND
LCMXO2-2000HE-6TG100I	2112	1.2 V	-6	Halogen-Free TQFP	100	IND
LCMXO2-2000HE-4MG132I	2112	1.2 V	-4	Halogen-Free csBGA	132	IND
LCMXO2-2000HE-5MG132I	2112	1.2 V	-5	Halogen-Free csBGA	132	IND
LCMXO2-2000HE-6MG132I	2112	1.2 V	-6	Halogen-Free csBGA	132	IND
LCMXO2-2000HE-4TG144I	2112	1.2 V	-4	Halogen-Free TQFP	144	IND
LCMXO2-2000HE-5TG144I	2112	1.2 V	-5	Halogen-Free TQFP	144	IND
LCMXO2-2000HE-6TG144I	2112	1.2 V	-6	Halogen-Free TQFP	144	IND
LCMXO2-2000HE-4BG256I	2112	1.2 V	-4	Halogen-Free caBGA	256	IND
LCMXO2-2000HE-5BG256I	2112	1.2 V	-5	Halogen-Free caBGA	256	IND
LCMXO2-2000HE-6BG256I	2112	1.2 V	-6	Halogen-Free caBGA	256	IND
LCMXO2-2000HE-4FTG256I	2112	1.2 V	-4	Halogen-Free ftBGA	256	IND
LCMXO2-2000HE-5FTG256I	2112	1.2 V	-5	Halogen-Free ftBGA	256	IND
LCMXO2-2000HE-6FTG256I	2112	1.2 V	-6	Halogen-Free ftBGA	256	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000UHE-4FG484I	2112	1.2 V	-4	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHE-5FG484I	2112	1.2 V	-5	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHE-6FG484I	2112	1.2 V	-6	Halogen-Free fpBGA	484	IND



MachXO2 Family Data Sheet Supplemental Information

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For Further Information

A variety of technical notes for the MachXO2 family are available on the Lattice web site.

- TN1198, Power Estimation and Management for MachXO2 Devices
- TN1199, MachXO2 sysCLOCK PLL Design and Usage Guide
- TN1201, Memory Usage Guide for MachXO2 Devices
- TN1202, MachXO2 sysIO Usage Guide
- TN1203, Implementing High-Speed Interfaces with MachXO2 Devices
- TN1204, MachXO2 Programming and Configuration Usage Guide
- TN1205, Using User Flash Memory and Hardened Control Functions in MachXO2 Devices
- TN1206, MachXO2 SRAM CRC Error Detection Usage Guide
- TN1207, Using TraceID in MachXO2 Devices
- TN1074, PCB Layout Recommendations for BGA Packages
- TN1087, Minimizing System Interruption During Configuration Using TransFR Technology
- AN8086, Designing for Migration from MachXO2-1200-R1 to Standard (non-R1) Devices
- AN8066, Boundary Scan Testability with Lattice sysIO Capability
- MachXO2 Device Pinout Files
- Thermal Management document
- · Lattice design tools

For further information on interface standards, refer to the following web sites:

- JEDEC Standards (LVTTL, LVCMOS, LVDS, DDR, DDR2, LPDDR): www.jedec.org
- PCI: www.pcisig.com

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